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**MANUFACTURING  
METROLOGY TEAM**

# **Case studies in X-ray computed tomography surface texture measurement**

**Adam Thompson**



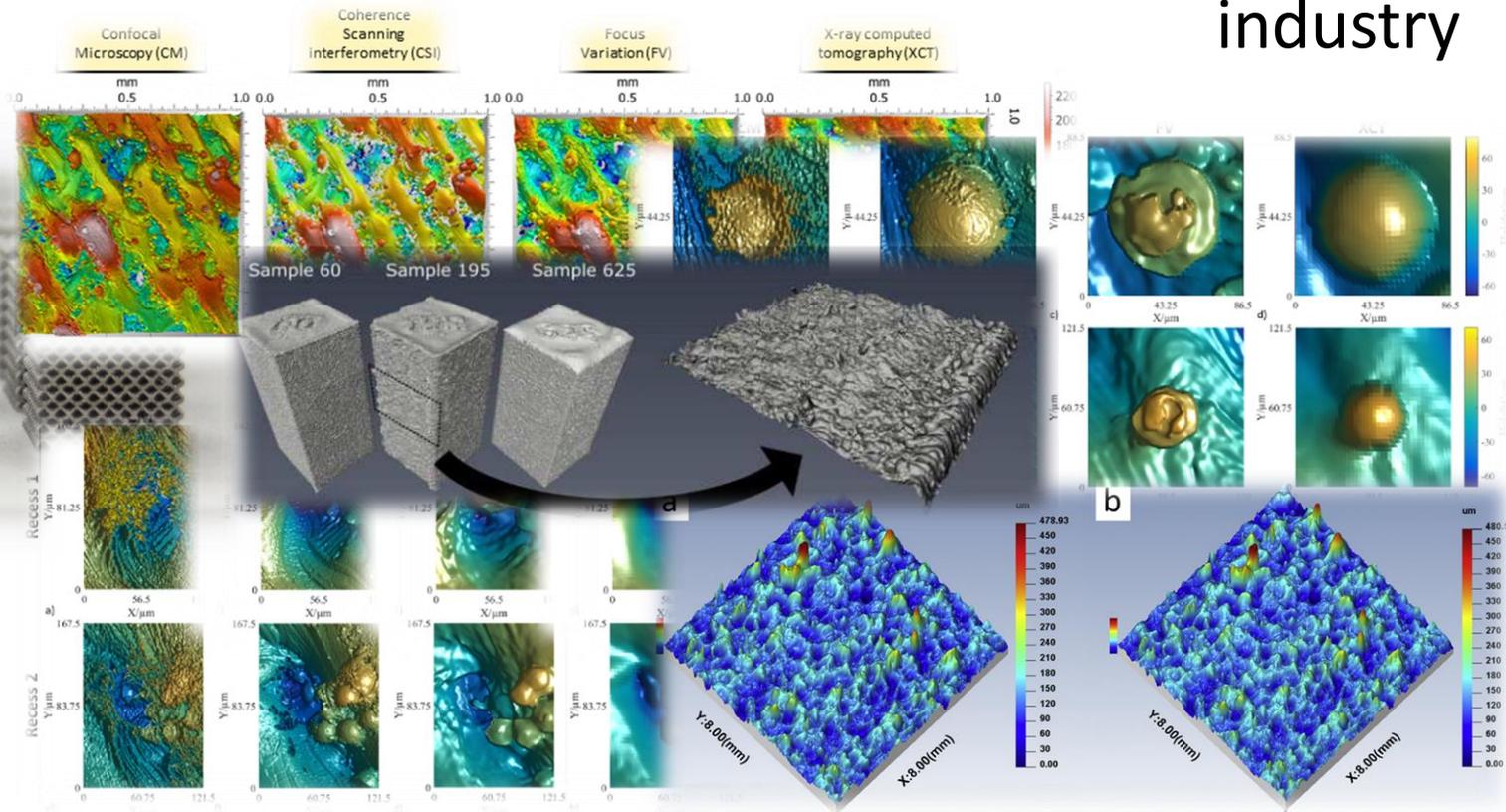
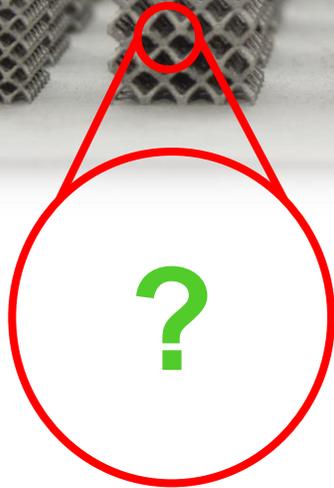
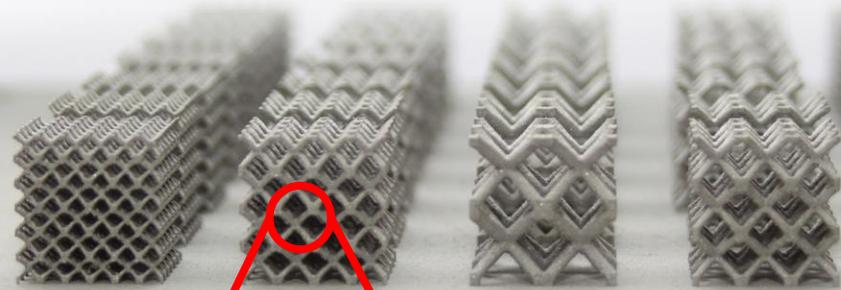
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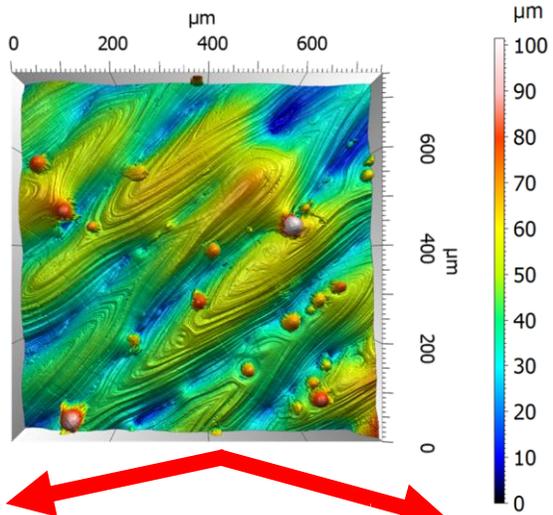
# Introduction

Until recently, measurement of internal and difficult-to-access surfaces was considered impossible

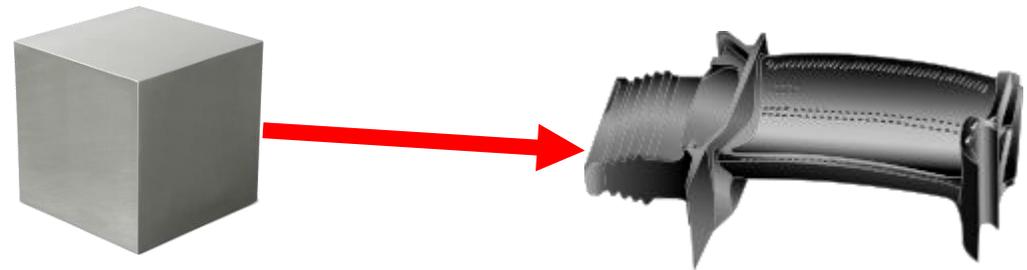
But recent advances have changed this thinking, and now people are measuring surfaces using XCT in research and industry



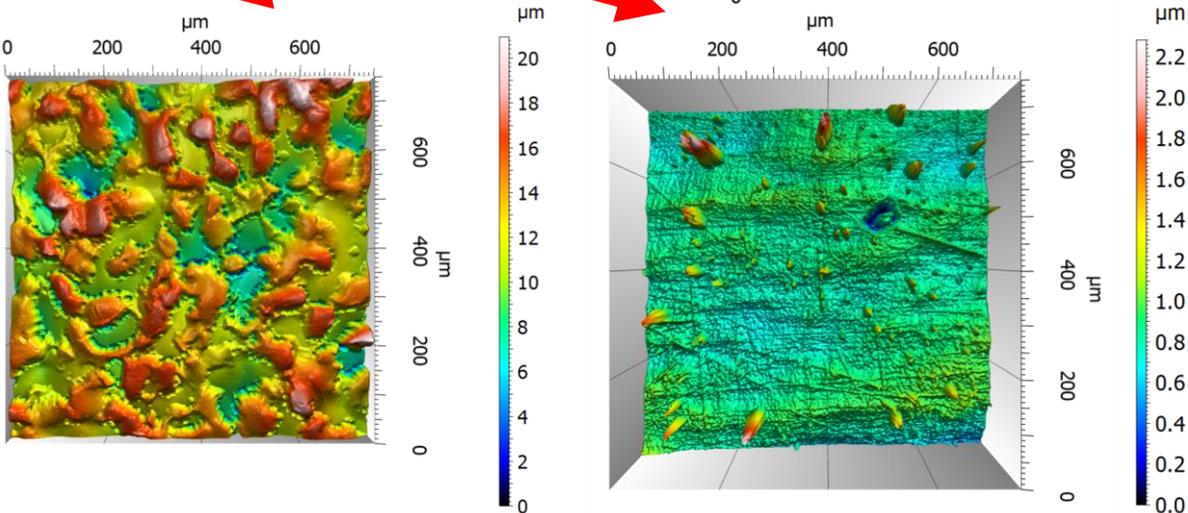
XCT has shown to be capable of measuring the relatively rough additively manufactured surfaces of today



But what about in an industrial environment?



Or about the surfaces of tomorrow?

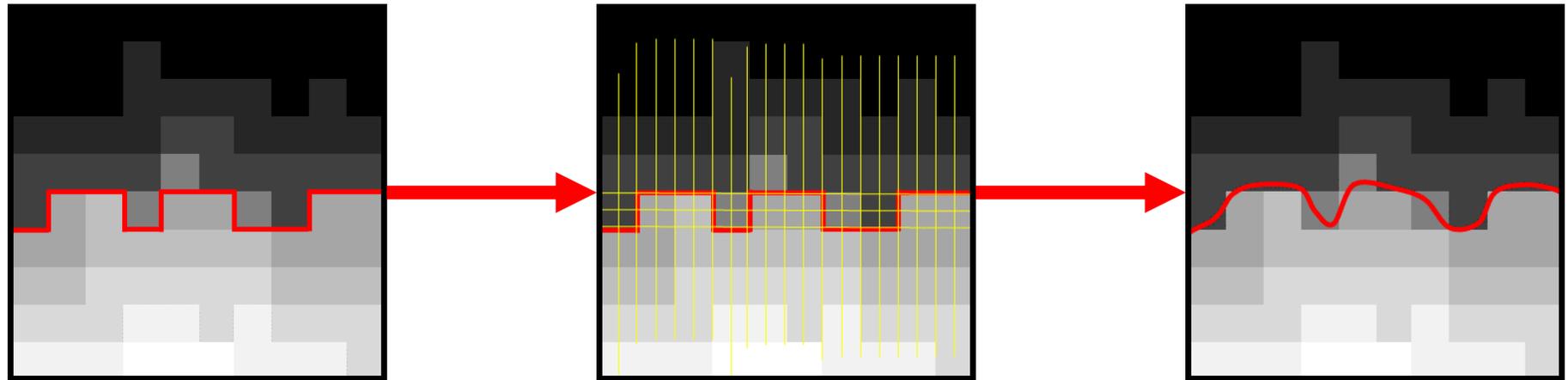


And what about when we need to measure much smoother surfaces?

We don't yet know how good we can get with XCT, because XCT resolution is ambiguous

Is it a voxel? Or is it smaller? (As software manufacturers would have us believe)

Local surface  
determination  
in VG Studio  
MAX



Until we can calibrate, we have to test empirically, because industry wants to measure these surfaces now

Keeping it relevant, let's test with industrial case studies



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# Case studies and methods

Additively manufactured Ti6Al4V cube of size (20 × 20 × 20) mm containing internal channels, supplied by 3TRPD

Internal and external rough surfaces, typical of surfaces examined in the literature

Supplied by 3TRPD

XCT measurements of whole part, then milled to allow access to surface of interest

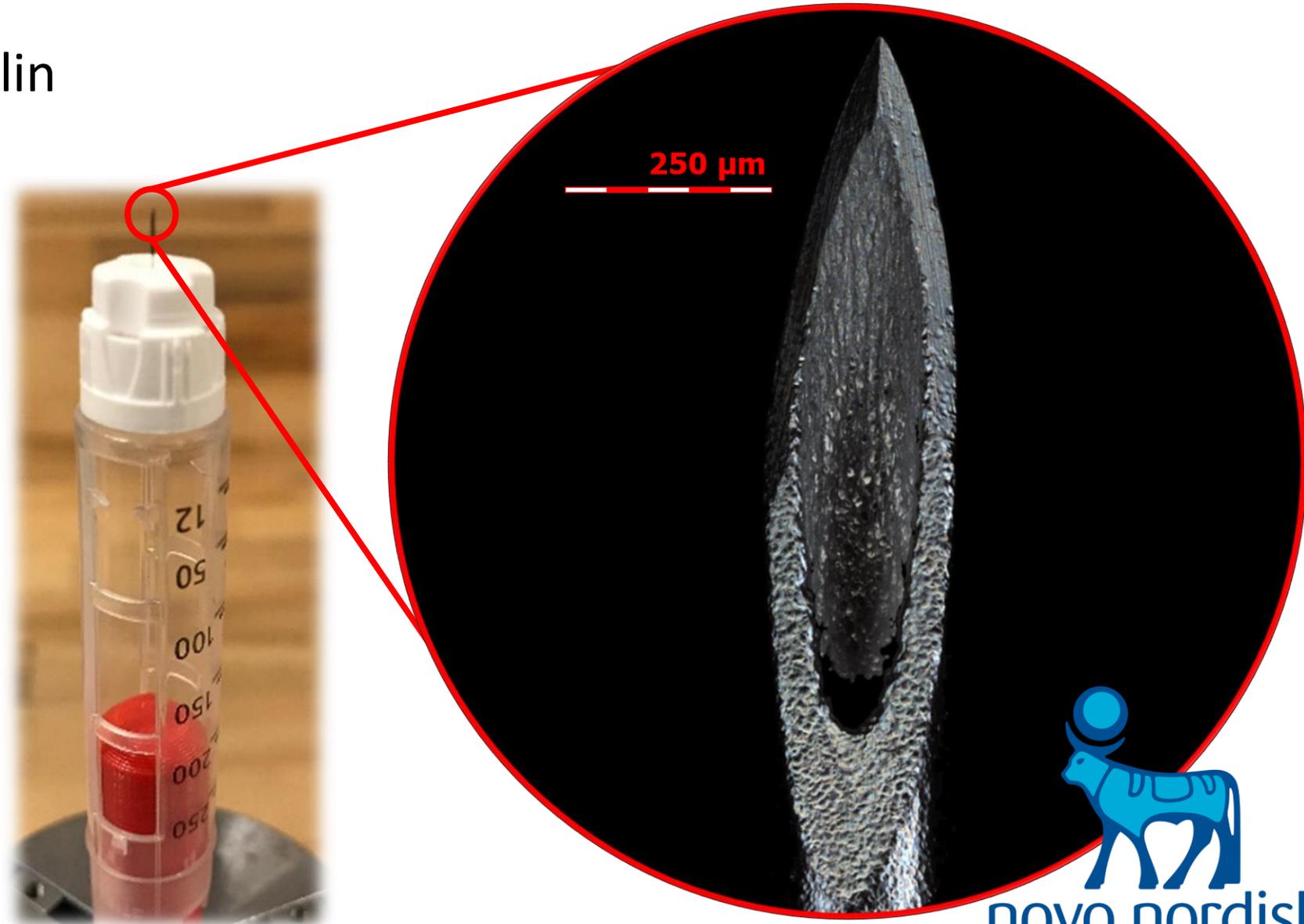


NovoNordisk 'market' insulin  
needle made from Silicone  
coated stainless steel

Externally smooth,  
internally rough

Surfaces of interest on the  
interior of the part

Accessible end of needle  
measured



Child's toy mask made of acrylonitrile butadiene styrene (ABS)

Smother than parts commonly measured using XCT

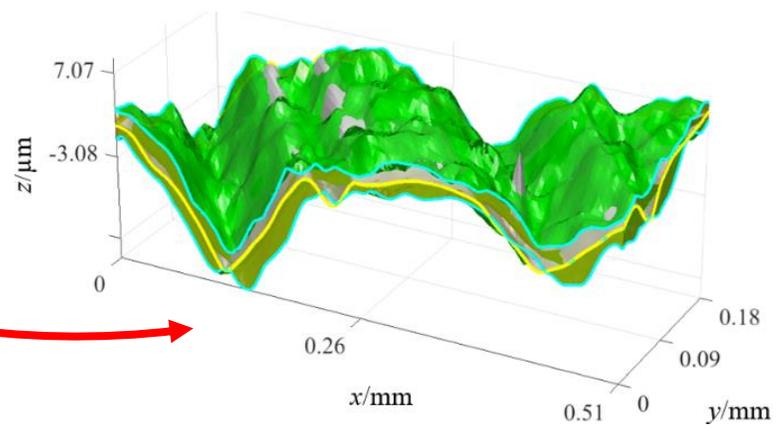
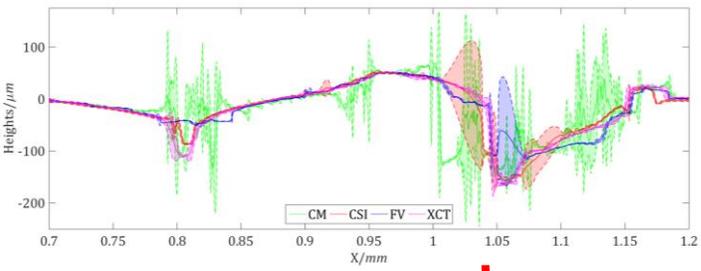
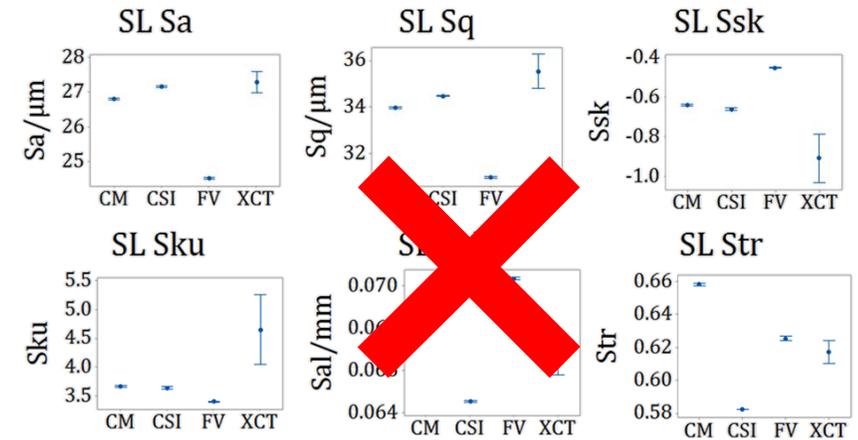
Complex form, with inaccessible surfaces

Accessible surface of 'nose' measured



Lots of work now shows that a simple parameter study will provide statistical discrepancies between measuring instruments, even when instruments' spatial measurement bandwidths are matched

Instead, we will perform a direct statistical comparison of topographies



We can then estimate surface repeatability (i.e. precision) from mean confidence interval width, and the average bias between data acquired using different systems (i.e. accuracy)

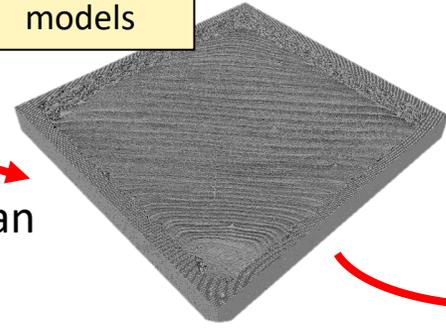
Modelling is based on building confidence intervals of z values at 95 % confidence at each x,y location of the topography. CI estimation is performed considering each x,y location as an independent variable and using t-distributions to estimate CIs.

XCT scanner

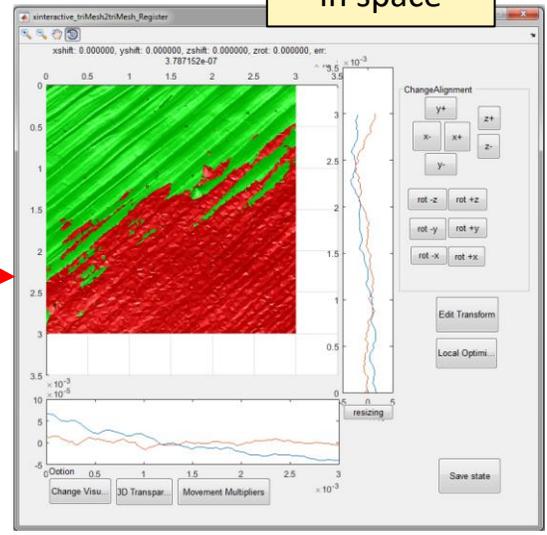


XCT scan

Triangulated models

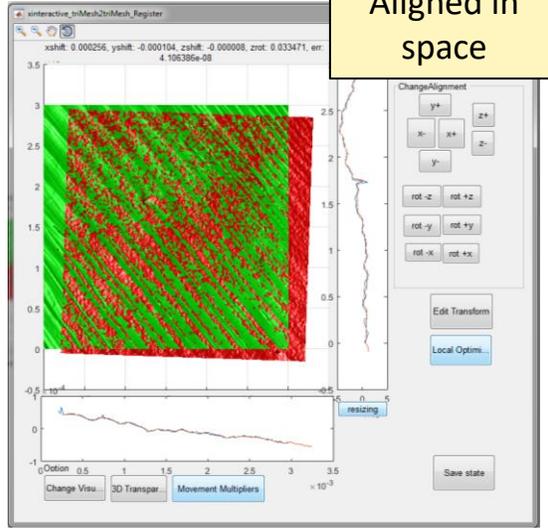


Unaligned in space



Alignment in 6 degrees of freedom

Aligned in space



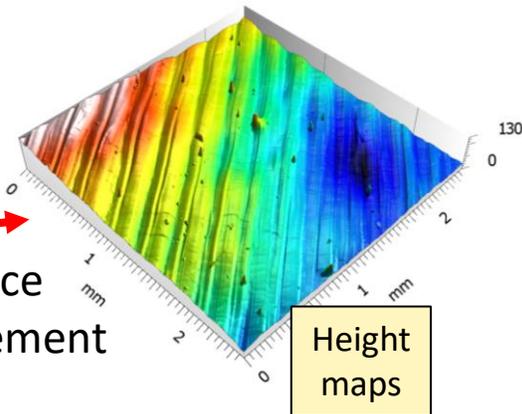
5 replicates taken for each measurement, of the same region of interest

Note: Images of instruments are *arbitrarily* chosen here as references – as with all our work, we are instrument agnostic

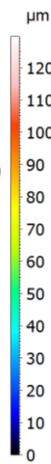


Focus variation microscopy (FV) and Coherence scanning interferometry (CSI)

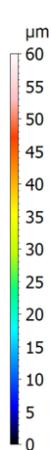
Surface measurement



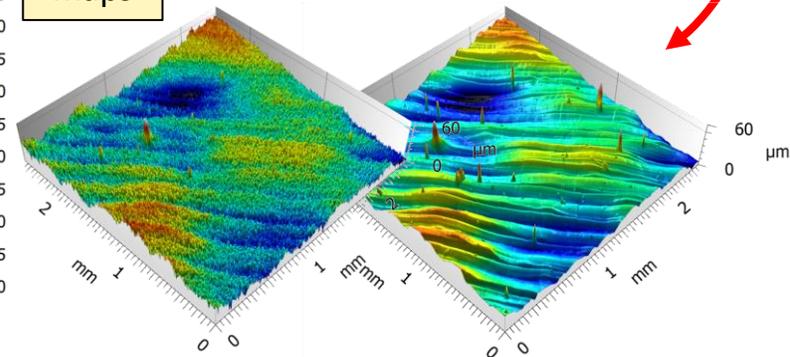
Height maps



Triangulation



Height maps



Raster scanning at defined pixel spacing, intrinsically matches bandwidths



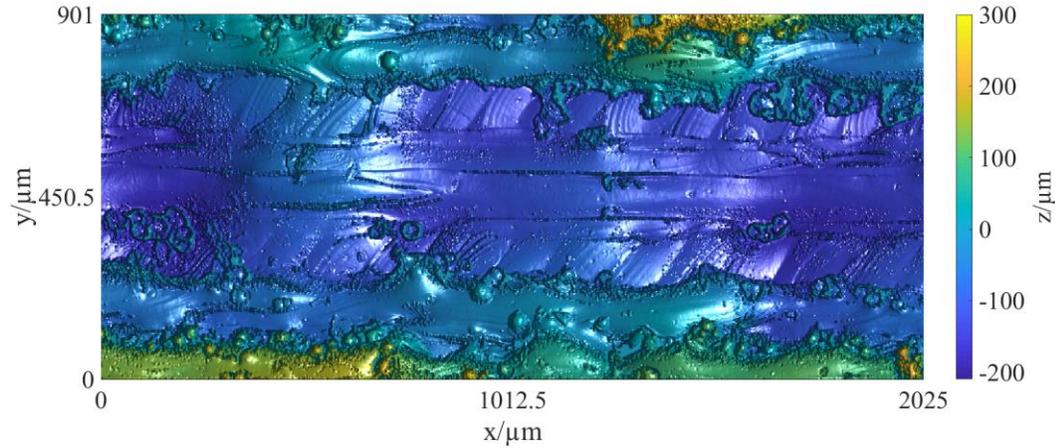
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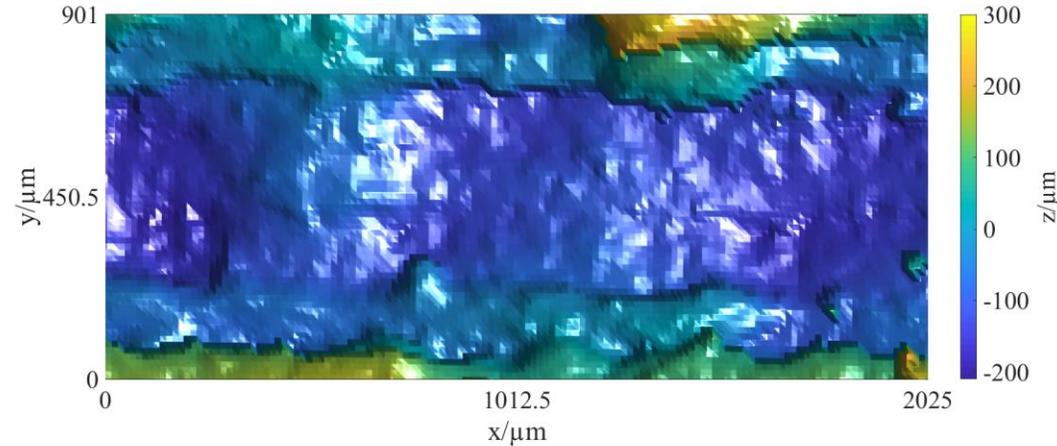
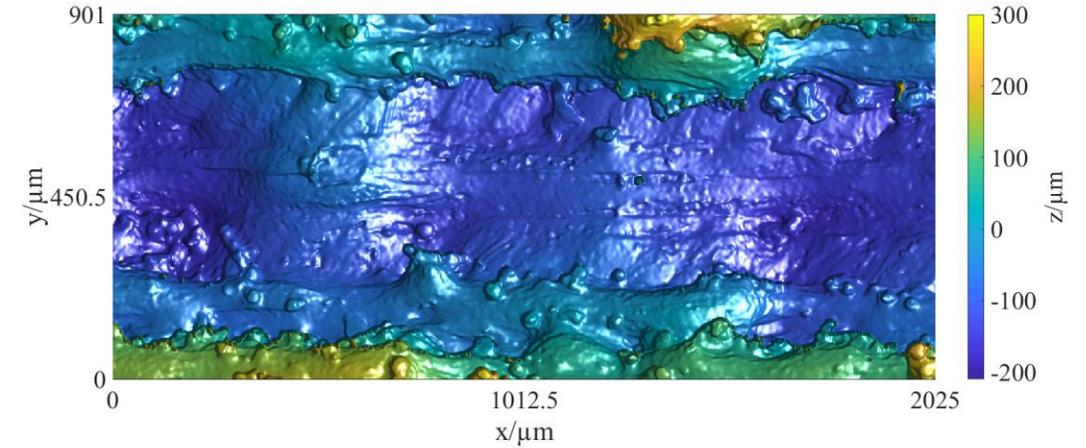
# Results and discussion

## Example individual datasets from each measurement setup

CSI



FV

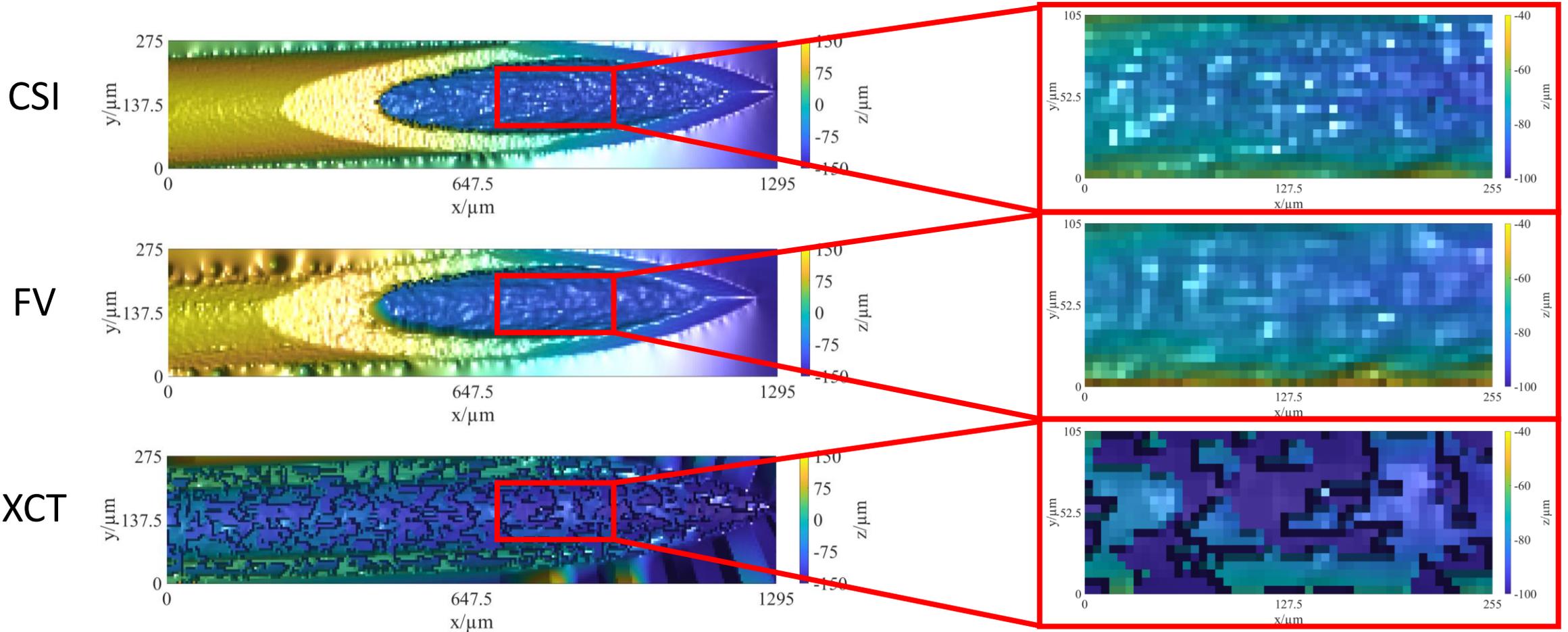


XCT

CSI objective: 20× (NA 0.40, lat res 0.68 μm)  
FV objective: (NA 0.40, lat res 3 μm)

XCT Voxel size: 18.2 μm  
Pixel spacing: 0.5 μm

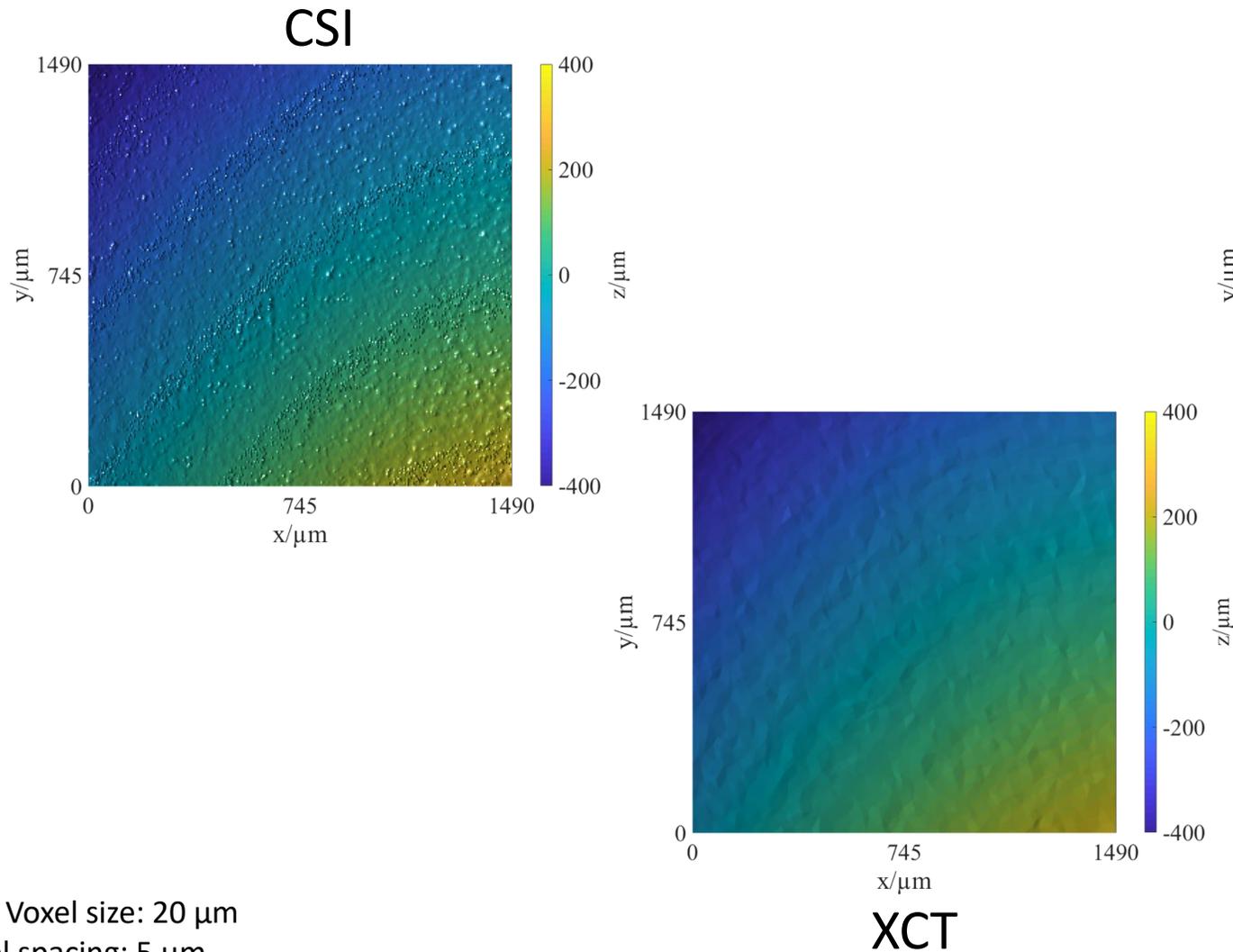
## Example individual datasets from each measurement setup



XCT Voxel size:  $5\ \mu\text{m}$   
Pixel spacing:  $5\ \mu\text{m}$

CSI objective:  $5.5\times$  (NA 0.15, lat res  $1.9\ \mu\text{m}$ )  
FV objective: (NA 0.40, lat res  $3\ \mu\text{m}$ )

## Example individual datasets from each measurement setup



Note: poor alignment between CSI and FV due to a lack of fiducials), so data must be reacquired of the correct area.

However, alignment between FV replicate measurements is good

Therefore, CI width information remains valid in this study but the bias should be discounted

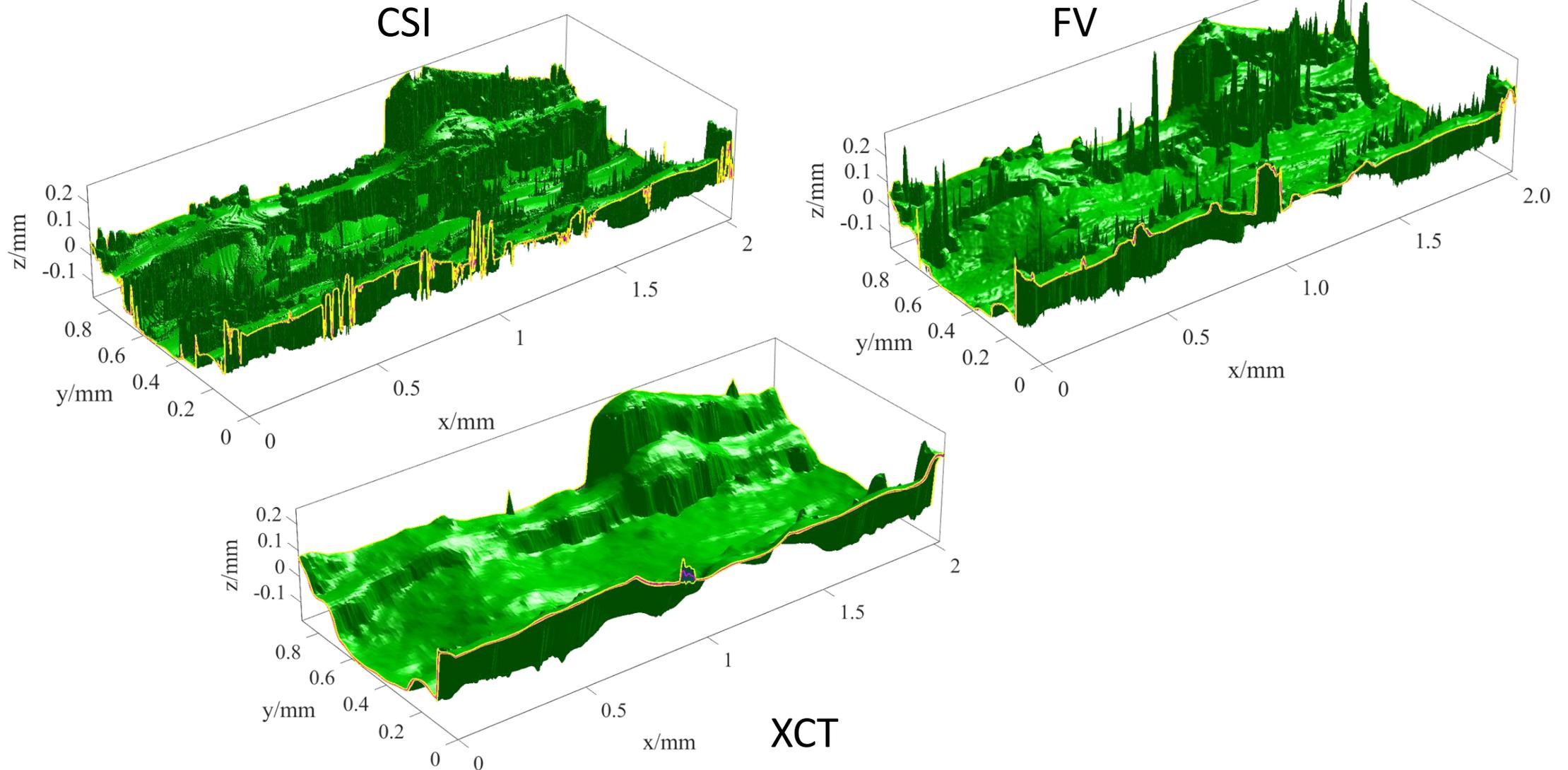
CSI objective: 5.5 $\times$  (NA 0.15, lat res 1.9  $\mu\text{m}$ )

FV objective: (NA 0.40, lat res 3  $\mu\text{m}$ )

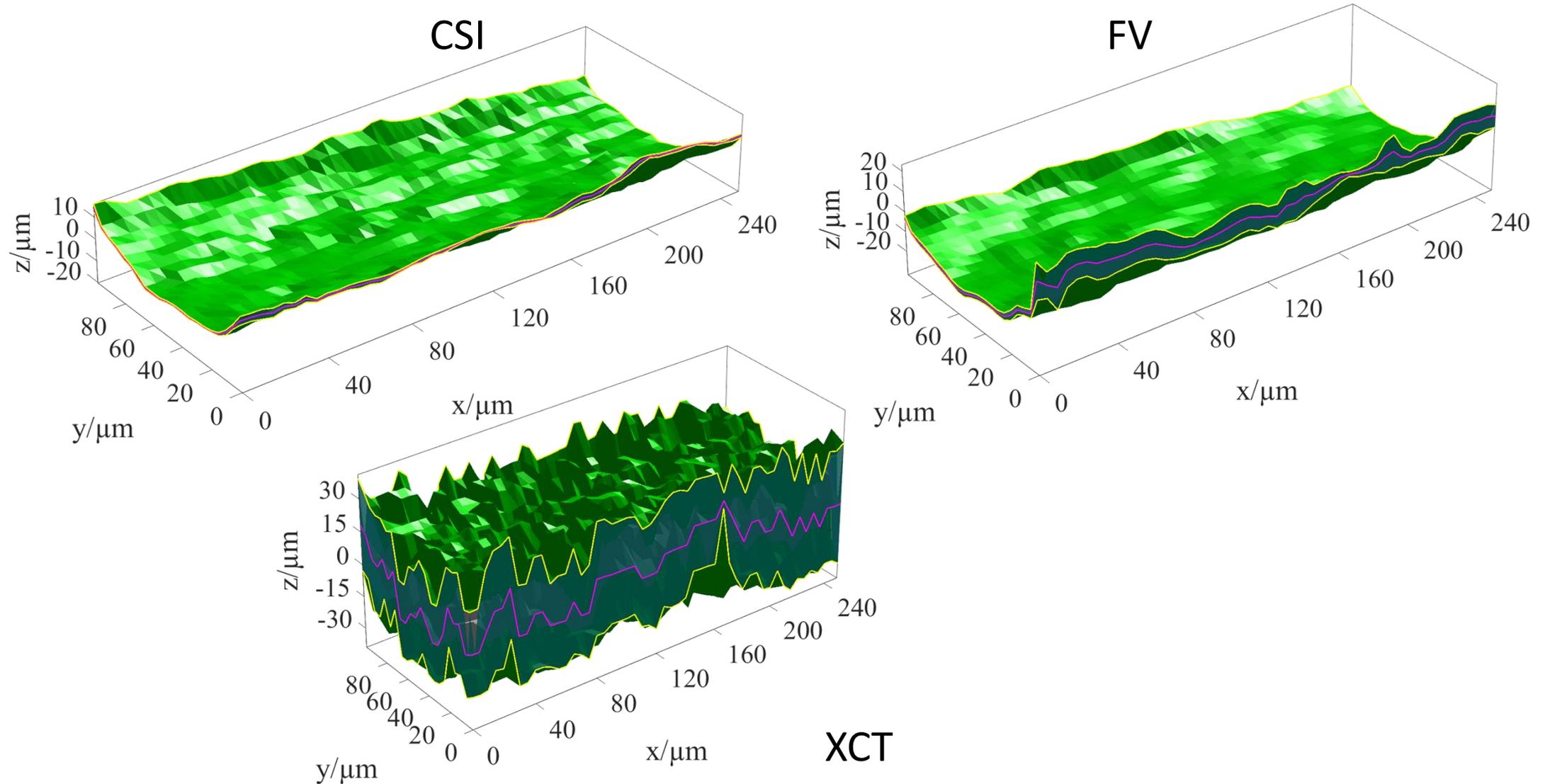
XCT Voxel size: 20  $\mu\text{m}$   
Pixel spacing: 5  $\mu\text{m}$

XCT

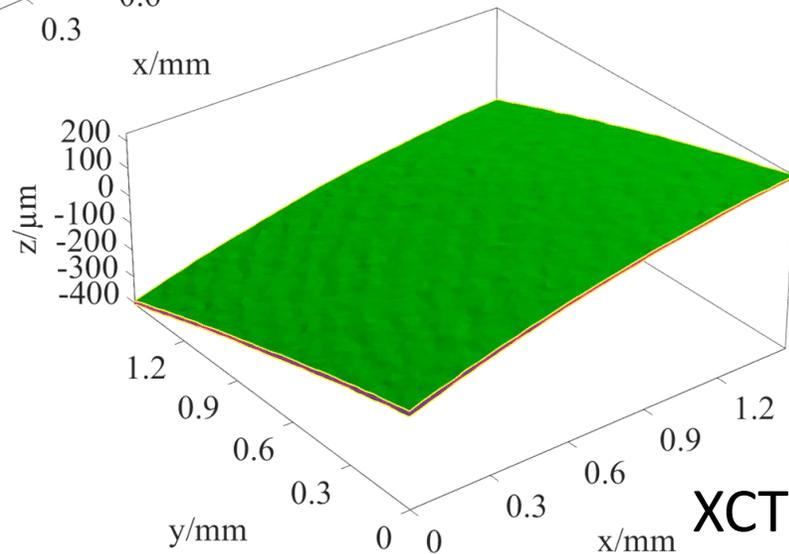
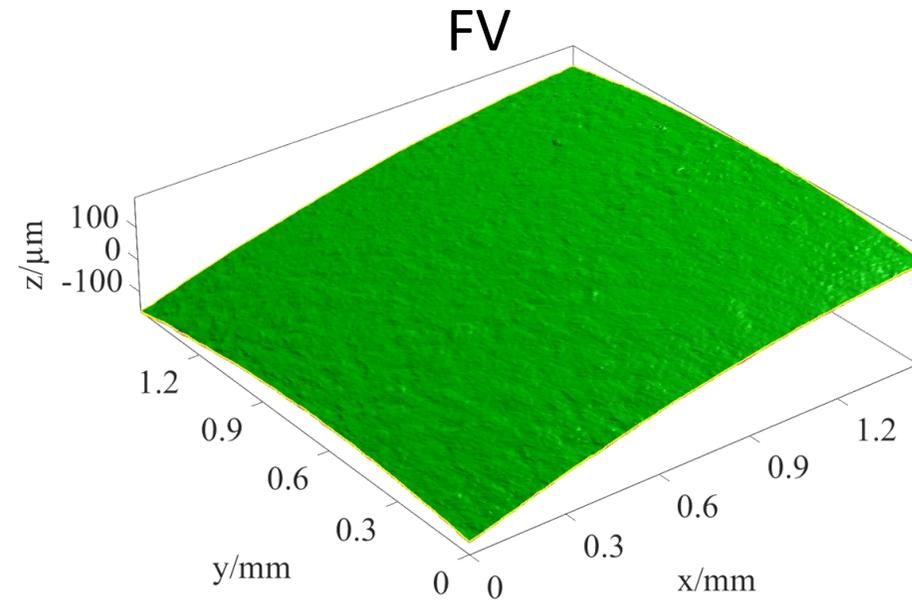
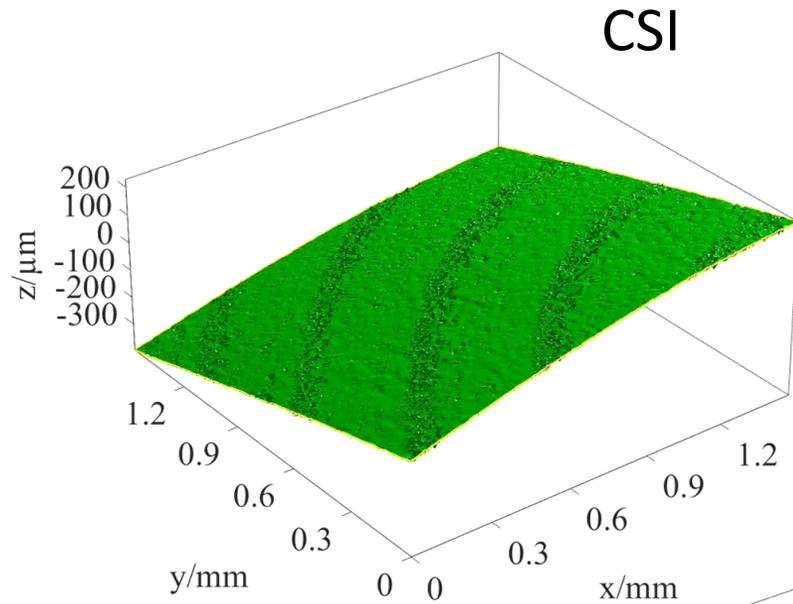
Mean surfaces, with upper and lower bounds at 95% confidence



Mean surfaces, with upper and lower bounds at 95% confidence

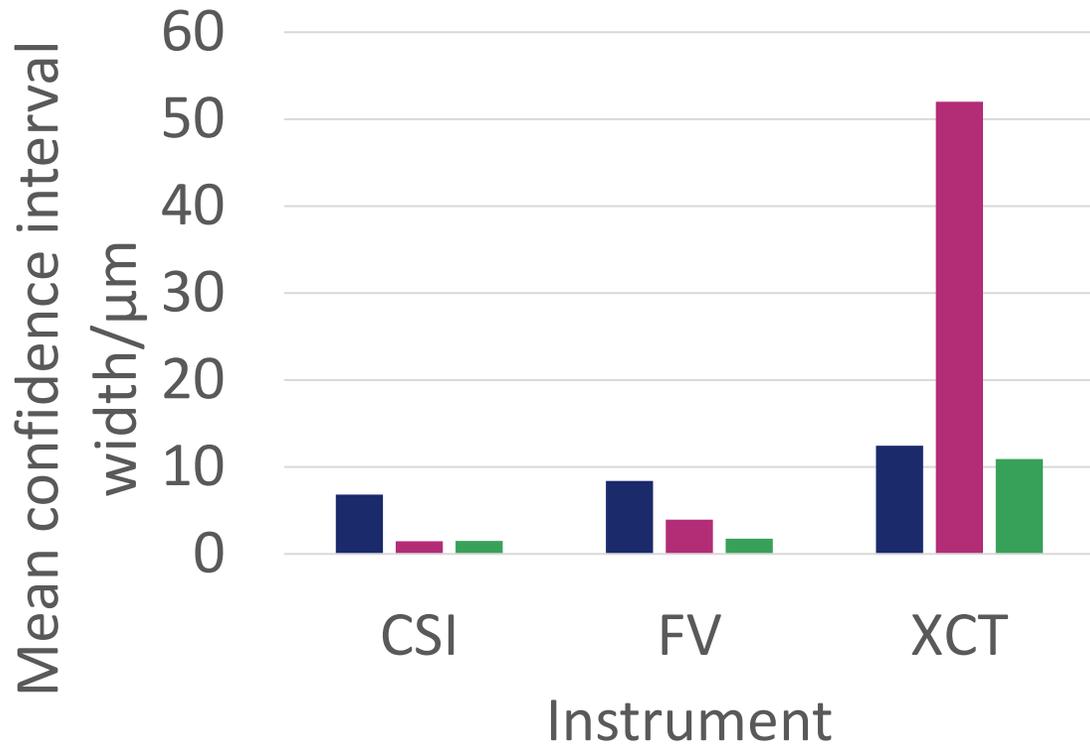


Mean surfaces, with upper and lower bounds at 95% confidence



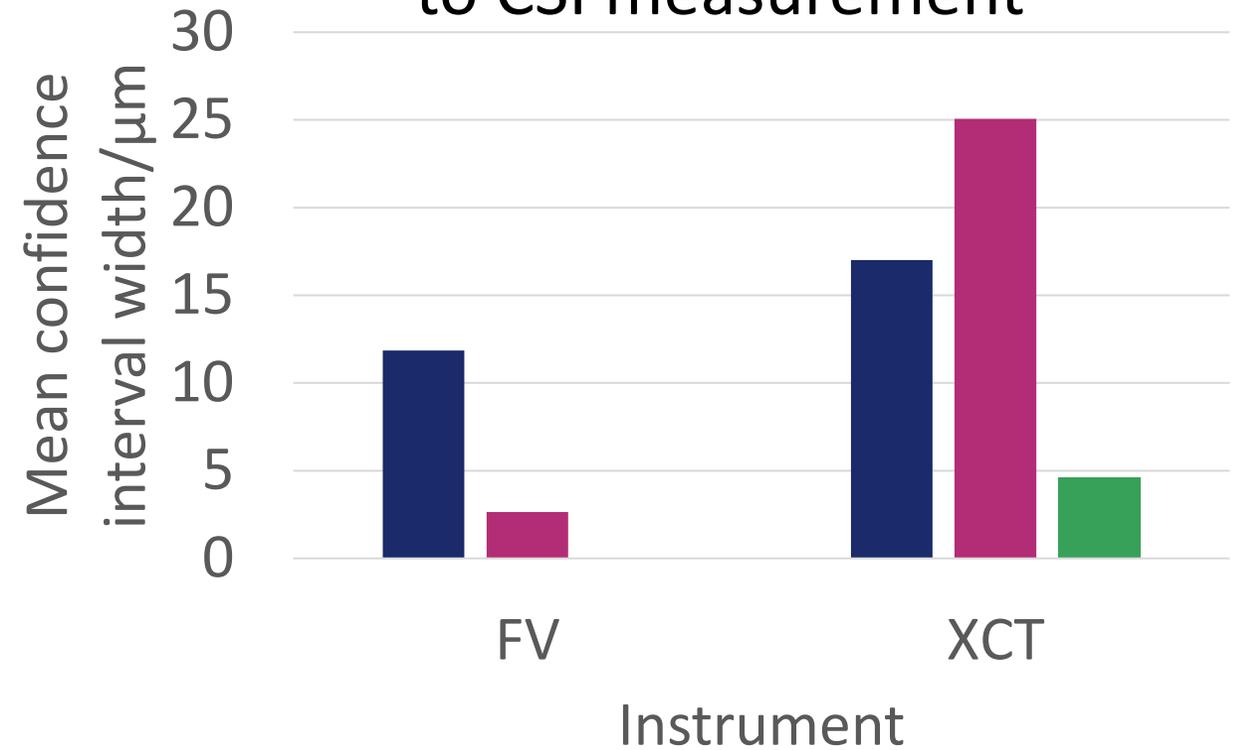
**(Precision)**

Repeatability from mean confidence interval width



**(Accuracy)**

Arithmetic average of bias in height determination with respect to CSI measurement



- Ti6Al4V Cube
- Market needle
- Mask nose

Note: CSI is *arbitrarily* chosen here as a reference, it does not necessarily represent the best measurement choice  
 Note: Bias between CSI and FV in Mask nose case discounted



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# Conclusions and outlook

XCT surface measurement has been now applied to industrial test cases

Case studies were of mixed success:

- In some cases, XCT was similarly repeatable to the optical methods, while arithmetic average bias between the XCT/optical datasets was comparable to the arithmetic average bias between the optical/optical datasets
- In other cases, XCT repeatability was poorer, and arithmetic average bias between the XCT/optical datasets was notably larger than the arithmetic average bias between the optical/optical datasets

XCT was clearly more capable of measuring the rougher surfaces than the smoother surfaces



These three case studies represent the first few of a program of case studies, demonstrating the use of XCT in industrial surface measurement

Steps can always be taken to optimise measurement instrument settings, and further measurement may result in improved results over those discussed in this talk

Calibration of XCT systems for surface measurement is the vital, logical next step



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# Manufacturing Metrology Team at Nottingham



# Thank you!

Thanks also to 3TRPD and NovoNordisk for samples, and DTI for XCT data



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